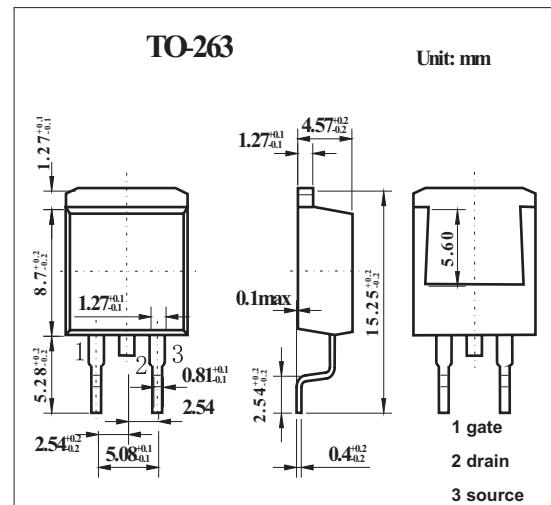
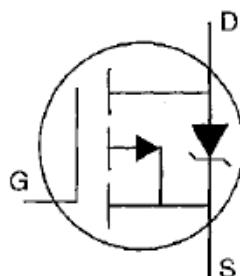


HEXFET® Power MOSFET

KRF9640S

■ Features

- Surface Mount
- Available in Tape & Reel
- Dynamic dv/dt Rating
- Repetitive Avalanche Rated
- P-Channel
- Fast Switching
- Ease of Paralleling



■ Absolute Maximum Ratings Ta = 25°C

Parameter	Symbol	Rating	Unit
Continuous Drain Current, Vgs @ -10V, Tc = 25°C	Id	-11	A
Continuous Drain Current, Vgs @ -10V, Tc = 100°C	Id	-6.8	
Pulsed Drain Current*1	Idm	-44	
Power Dissipation Tc = 25°C	Pd	125	W
Power Dissipation (PCB Mount) Ta = 25°C *3		3	
Linear Derating Factor		1	W/°C
Linear Derating Factor (PCB Mount) *3		0.025	
Gate-to-Source Voltage	Vgs	±20	V
Single Pulse Avalanche Energy *4	Eas	700	mJ
Avalanche Current	Iar	-11	A
Repetitive Avalanche Energy	Ear	13	mJ
Peak Diode Recovery dv/dt *2	dv/dt	-5	V/ns
Operating Junction and Storage Temperature Range	Tj, Tstg	-55 to + 150	°C
Junction-to-Case	Rθ JC	1	°C/W
Junction-to-Ambient (PCB Mounted) *3	Rθ JA	40	°C/W
Junction-to-Ambient	Rθ JA	62	°C/W

*1Repetitive rating; pulse width limited by max. junction temperature.

*2 Isd ≤ -11A, di/dt ≤ 150A/μ s, Vdd ≤ V(BR)DSS, TJ ≤ 150°C

* 3 When mounted on 1" square PCB

*4 VDD=-50V,startin TJ=25°C,L=8.7mH,RG=25Ω ,IAS=-11A

KRF9640S■ Electrical Characteristics $T_a = 25^\circ\text{C}$

Parameter	Symbol	Testconditons	Min	Typ	Max	Unit
Drain-to-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = -250 \mu\text{A}$	-200			V
Breakdown Voltage Temp. Coefficient	$\Delta V_{(\text{BR})\text{DSS}}/\Delta T_J$	$I_D = -1\text{mA}$, Reference to 25°C		-0.20		$\text{V}/^\circ\text{C}$
Static Drain-to-Source On-Resistance	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}} = -10\text{V}, I_D = -6.6\text{A}^*\text{1}$			0.5	Ω
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = -250 \mu\text{A}$	-2.0		-4.0	V
Forward Transconductance	g_{fs}	$V_{\text{DS}} = -50\text{V}, I_D = -6.6\text{A}^*\text{1}$	4.1			S
Drain-to-Source Leakage Current	I_{DSS}	$V_{\text{DS}} = -200\text{V}, V_{\text{GS}} = 0\text{V}$		-100		μA
		$V_{\text{DS}} = -160\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 125^\circ\text{C}$		-500		
Gate-to-Source Forward Leakage	I_{GSS}	$V_{\text{GS}} = 20\text{V}$		-100		nA
Gate-to-Source Reverse Leakage		$V_{\text{GS}} = -20\text{V}$		100		
Total Gate Charge	Q_g	$I_D = -11\text{A}$		44		
Gate-to-Source Charge	Q_{gs}	$V_{\text{DS}} = -160\text{V}$		7.1		nC
Gate-to-Drain ("Miller") Charge	Q_{gd}	$V_{\text{GS}} = -10\text{V}, ^*\text{1}$		27		
Turn-On Delay Time	$t_{\text{d}(\text{on})}$	$V_{\text{DD}} = -100\text{V}$		14		
Rise Time	t_r	$I_D = -11\text{A}$		43		
Turn-Off Delay Time	$t_{\text{d}(\text{off})}$	$R_G = 9.1 \Omega$		39		
Fall Time	t_f	$R_D = 8.6 \Omega^*\text{1}$		38		
Internal Drain Inductance	L_D	Between lead, 6 mm (0.25in.) from package and center of die contact		4.5		nH
Internal Source Inductance	L_S			7.5		
Input Capacitance	C_{iss}	$V_{\text{GS}} = 0\text{V}$		1200		
Output Capacitance	C_{oss}	$V_{\text{DS}} = -25\text{V}$		370		pF
Reverse Transfer Capacitance	C_{rss}	$f = 1.0\text{MHz}$		81		
Continuous Source Current (Body Diode)	I_S	MOSFET symbol showing the integral reverse p-n junction diode.			-11	A
Pulsed Source Current (Body Diode) *2	I_{SM}				-44	
Diode Forward Voltage	V_{SD}	$T_J = 25^\circ\text{C}, I_S = -1.1\text{A}, V_{\text{GS}} = 0\text{V}^*\text{1}$			-5.0	V
Reverse Recovery Time	t_{rr}	$T_J = 25^\circ\text{C}, I_F = -1.1\text{A}$		250	300	ns
Reverse Recovery Charge	Q_{rr}	$dI/dt = 100\text{A}/\mu\text{s}^*\text{1}$		2.9	3.6	μC
Forward Turn-On Time	t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S+L_D)				

*1 Pulse width $\leq 300 \mu\text{s}$; duty cycle $\leq 2\%$.

*2 Repetitive rating; pulse width limited by max

